

Dieter G Ast

List of Publications by Year in descending order

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176
citing authors

#	ARTICLE	IF	CITATIONS
1	Hybrid reflections from multiple x-ray scattering in epitaxial oxide films. Applied Physics Letters, 2017, 111, 131903.	3.3	11
2	Effects of RF Sputtering Parameters on C-axis Aligned Crystalline (CAAC) InGaZnO ₄ Films Using Design of Experiment (DOE) Approach. ECS Journal of Solid State Science and Technology, 2016, 5, P368-P375.	1.8	6
3	High mobility, dual layer, c-axis aligned crystalline/amorphous IGZO thin film transistor. Applied Physics Letters, 2015, 107, 183503.	3.3	40
4	45.2: Effects of RF Sputtering Parameters and Film Composition on C-axis Aligned Crystalline (CAAC) IGZO Films. Digest of Technical Papers SID International Symposium, 2015, 46, 677-680.	0.3	21
5	21.4: Deposition Conditions and HRTEM Characterization of CAAC IGZO. Digest of Technical Papers SID International Symposium, 2015, 46, 308-311.	0.3	25
6	Chemical Etch Rate and X-Ray Structure of Reactive Sputtered c-Axis Aligned Crystalline In _x Ga _y Zn _z O ₄ Films. ECS Journal of Solid State Science and Technology, 2015, 4, Q43-Q45.	1.8	24
7	High mobility amorphous InGaZnO ₄ thin film transistors formed by CO ₂ laser spike annealing. Applied Physics Letters, 2015, 106, .	3.3	24
8	Characterization of reactively sputtered c-axis aligned nanocrystalline InGaZnO ₄ . Applied Physics Letters, 2014, 105, .	3.3	42
9	Kinetics of silicide-induced crystallization of polycrystalline thin-film transistors fabricated from amorphous chemical-vapor deposition silicon. Applied Physics Letters, 1998, 72, 803-805.	3.3	41
10	Instabilities in the resistivity of intrinsic polysilicon resistors during hydrogenation: Role of sodium and cooling kinetics. Journal of Applied Physics, 1994, 76, 3579-3582.	2.5	1
11	A Misfit Dislocation Blocking Mechanism in Continuous InGaAs Layers Grown on Patterned GaAs. Materials Research Society Symposia Proceedings, 1993, 308, 401.	0.1	0
12	Oxidation of Epitaxial- and Polycrystalline-SiGe Alloys. Materials Research Society Symposia Proceedings, 1993, 326, 227.	0.1	2
13	Anomalous Behavior in the Resistivity of N-I-N Polysilicon Resistors After Hydrogenation. Materials Research Society Symposia Proceedings, 1992, 262, 389.	0.1	0
14	The thermal stability of lattice mismatched InGaAs grown on patterned GaAs. Journal of Electronic Materials, 1991, 20, 703-708.	2.2	10
15	Measurements of Grain Boundary Trap Density and Hydrogen Diffusivity in Polycrystalline Silicon Fet's. Materials Research Society Symposia Proceedings, 1990, 182, 341.	0.1	7
16	Creep Deformation of Ultrafine Grained Ni ₇ 5B1 7Si8. Materials Research Society Symposia Proceedings, 1985, 58, 421.	0.1	1
17	Rapid Solidification Of Composite Materials. Materials Research Society Symposia Proceedings, 1983, 28, 189.	0.1	5
18	The Structure of a Near Coincidence $\Sigma=5$, [001] Twist Boundary in Silicon. Materials Research Society Symposia Proceedings, 1982, 14, 369.	0.1	4

#	ARTICLE	IF	CITATIONS
19	Ebic/Tem Investigation of Defects in Solar Cell Silicon. Materials Research Society Symposia Proceedings, 1981, 5, 167.	0.1	3
20	Characterization of Defects in Silicon Ribbons By Combined Ebic and Hvem. Materials Research Society Symposia Proceedings, 1980, 2, 297.	0.1	1
21	Mechanical properties of methanol crazes in poly(methyl methacrylate). Journal of Polymer Science, Polymer Physics Edition, 1978, 16, 349-366.	1.0	19
22	Holographic interferometry of crazes in polycarbonate. Journal of Applied Physics, 1974, 45, 4220-4228.	2.5	16
23	Optical Simulation of the Origin of Contrast in the Electron Microscope. American Journal of Physics, 1971, 39, 1164-1168.	0.7	3